

γD

100V N-Channel Enhancement Mode MOSFET

Description

The AP20N10D uses advanced trench technology

to provide excellent $R_{\text{DS}(\text{ON})},$ low gate charge and

operation with gate voltages as low as 4.5V. This

device is suitable for use as a

Battery protection or in other Switching application.

General Features

V_{DS} = 100V I_D =20A

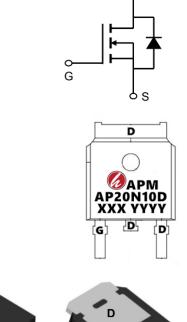
 $R_{\text{DS(ON)}}$ Type: 65m Ω @ V_{GS}=10V

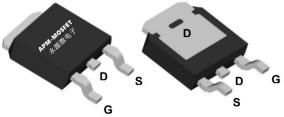
Application

Lithium battery protection

Wireless impact

Mobile phone fast charging





Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP20N10D	TO-252-3L	AP20N10D XXX YYYY	2500

Absolute Maximum Ratings (TC=25 °C unless otherwise noted)

Symbol	Parameter	Rating	Units
VDS	Drain-Source Voltage	100	V
VGS	Gate-Source Voltage	±20	V
I _D @T _C =25℃	Drain Current, V _{GS} @ 10V	20	А
I _D @T _C =100℃	Drain Current, V _{GS} @ 10V	13	А
IDM	Pulsed Drain Current ¹	57.9	А
P₀@T₀=25℃	Total Power Dissipation	30	W
P₀@T _A =25℃	Total Power Dissipation ³	2.7	W
EAS	Single Pulse Avalanche Energy ⁴	7	mJ
TSTG	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C
RθJA	Maximum Thermal Resistance, Junctionambient	55	°C/W
RθJC	Maximum Thermal Resistance, Junction-case	5.1	°C/W

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Electrical Characteristics@Tj=25°C(unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Units
V(BR)DSS	Drain-Source Breakdown Voltage	VGS=0V, ID=250µA	100	107	-	V
IDSS	Zero Gate Voltage Drain Current	VDS=100V, VGS=0V,	-	-	1.0	μA
IGSS	Gate to Body Leakage Current	VDS=0V, VGS=±20V	-	-	±100	nA
VGS(th)	Gate Threshold Voltage	VDS=VGS, ID=250µA	1.2	1.85	2.5	V
		VGS=10V, ID=5A	-	65	85	mΩ
RDS(on)	Static Drain-Source on-Resistance note3	VGS=4.5V, ID=3A	-	75	100	Μω
g fs	Forward Transconductance	V DS =5V , I D =5A		14		S
RG	Gate Resistance	VDS = 0V, VGS =0V,f =1MHz		3		Ω
Ciss	Input Capacitance		-	1100	-	pF
Coss	Output Capacitance	VDS=15V, VGS=0V, f=1.0MHz	-	55	-	pF
Crss	Reverse Transfer Capacitance		-	40	-	pF
Qg	Total Gate Charge	VDS=50V,	-	11.9	-	nC
Qgs	Gate-Source Charge	ID=5A,	-	2.8	-	nC
Qgd	Gate-Drain("Miller") Charge	VGS=10V	-	1.7	-	nC
td(on)	Turn-on Delay Time		-	3.8	-	ns
tr	Turn-on Rise Time	VDS=30V, ID=5A,	-	25.8	-	ns
td(off)	Turn-off Delay Time	RG=1.8Ω, VGS=10V	-	16	-	ns
tf	Turn-off Fall Time		-	8.8	-	ns
IS	Continuous Source Current1,5	VG=VD=0V , Force Current	-	-	14.6	А
ISM	Pulsed Source Current2,5		-	-	25	А
VSD	Diode Forward Voltage2	VGS=0V, IS=10A	-	-	1.2	V

Notes:

 $1_{\mbox{\tiny V}}$ The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.

2. The data tested by pulsed , pulse width \leq 300us , duty cycle \leq 2%

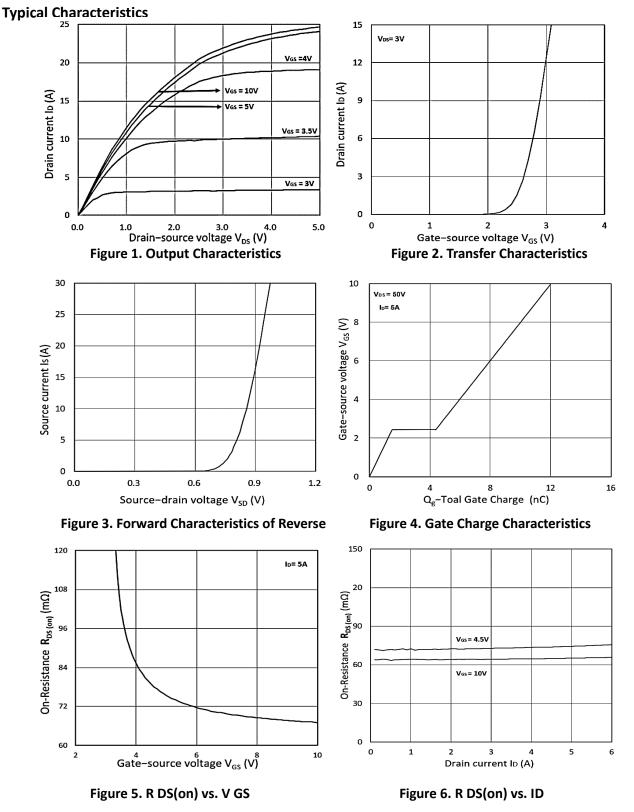
3、The EAS data shows Max. rating . The test condition is VDD =80V,VGS =10V,L=0.1mH,IAS =7A

4. The power dissipation is limited by 150° C junction temperature

5. The data is theoretically the same as I D and I DM , in real applications , should be limited by total power dissipation



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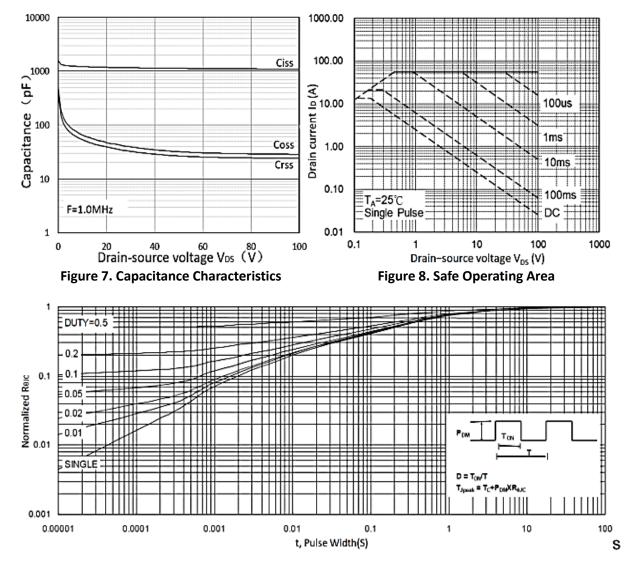
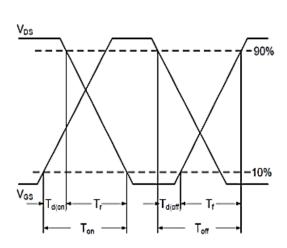
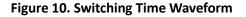


Figure 9. Normalized Maximum Transient Thermal Impedance





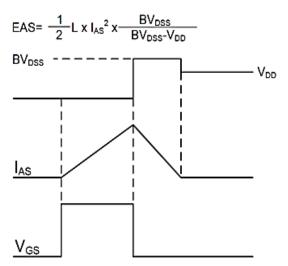
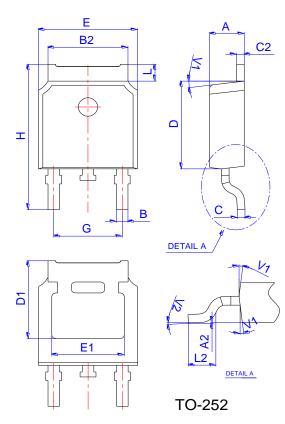


Figure 11. Unclamped Inductive Switching Waveform 🛛 🔶



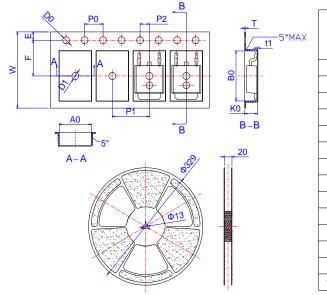
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Package Mechanical Data



	Dimensions						
Ref.	Millimeters			Inches			
	Min.	Тур.	Max.	Min.	Тур.	Max.	
A	2.10		2.50	0.083		0.098	
A2	0		0.10	0		0.004	
В	0.66		0.86	0.026		0.034	
B2	5.18		5.48	0.202		0.216	
С	0.40		0.60	0.016		0.024	
C2	0.44		0.58	0.017		0.023	
D	5.90		6.30	0.232		0.248	
D1	5.30REF			0.209REF			
E	6.40		6.80	0.252		0.268	
E1	4.63			0.182			
G	4.47		4.67	0.176		0.184	
н	9.50		10.70	0.374		0.421	
L	1.09		1.21	0.043		0.048	
L2	1.35		1.65	0.053		0.065	
V1		7°			7°		
V2	0°		6°	0°		6°	

Reel Spectification-TO-252



	Dimensions					
Ref.	Millimeters			Inches		
	Min.	Тур.	Max.	Min.	Тур.	Max.
W	15.90	16.00	16.10	0.626	0.630	0.634
Е	1.65	1.75	1.85	0.065	0.069	0.073
F	7.40	7.50	7.60	0.291	0.295	0.299
D0	1.40	1.50	1.60	0.055	0.059	0.063
D1	1.40	1.50	1.60	0.055	0.059	0.063
P0	3.90	4.00	4.10	0.154	0.157	0.161
P1	7.90	8.00	8.10	0.311	0.315	0.319
P2	1.90	2.00	2.10	0.075	0.079	0.083
A0	6.85	6.90	7.00	0.270	0.271	0.276
B0	10.45	10.50	10.60	0.411	0.413	0.417
K0	2.68	2.78	2.88	0.105	0.109	0.113
Т	0.24		0.27	0.009		0.011
t1	0.10			0.004		
10P0	39.80	40.00	40.20	1.567	1.575	1.583



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Edition	Date	Change
Rve1.0	2020/1/31	Initial release

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